

Notice of References Cited	Application/Control No. 10/569,517		Applicant(s)/Patent Under Reexamination MAYER ET AL.	
	Examiner EVAN H. LANGDON		Art Unit 3654	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,383,772 B2	06-2008	Boppel et al.	101/228
*	B	US-7,311,234 B2	12-2007	Solberg, Bruce Jerome	226/97.3
*	C	US-5,423,468 A	06-1995	Liedtke, Rudolph J.	242/615.12
*	D	US-6,427,941 B1	08-2002	Hikita, Shinji	242/615.12
*	E	US-6,302,353 B1	10-2001	Motegi et al.	242/615.12
*	F	US-6,004,432 A	12-1999	Page et al.	162/281
*	G	US-3,567,093 A	03-1971	Johnson, Lloyd W.	242/615.12
*	H	US-7,275,709 B2	10-2007	Weis, Anton	242/615.12
*	I	US-6,488,194 B1	12-2002	Couturier, Dennis P.	226/95
*	J	US-5,233,919 A	08-1993	Fecteau et al.	242/615.12
*	K	US-4,888,848 A	12-1989	Serracant-Clermont et al.	15/309.1
*	L	US-7,025,303 B2	04-2006	Meyer, Helmut	242/615.12
*	M	US-6,722,608 B1	04-2004	Gavit et al.	242/615.12

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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